

<b>Notice of References Cited</b>	Application/Control No. 09/664,565	Applicant(s)/Patent Under Reexamination NAIK, TEJAS	
	Examiner Hanh Nguyen	Art Unit 2662	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,856,602 B1	02-2005	Westberg, Lars	370/254
	B	US-5,699,347	12-1997	Callon, Ross W.	370/238
	C	US-5,854,899 A	12-1998	Callon et al.	709/238
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

**Notic of References Cited**

Application/Control No.

09/664,565

Applicant(s)/Patent Under  
Reexamination  
NAIK, TEJAS

Examiner

Hanh Nguyen

Art Unit

2662

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6304577 B1	10-2001	Nagami et al.	370/409
	B	US-5699347	12-1997	Callon	370/238
	C	US-6229787 B1	05-2001	Byrne	370/218
	D	US-6363072 B1	03-2002	Furuichi	370/395
	E	US-5854899	12-1998	Callon et al.	395/200.68
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 09/664,565	Applicant(s)/Patent Under Reexamination NAIK, TEJAS	
	Examiner Hanh Nguyen	Art Unit 2662	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6173324 B1	01-2001	D'Souza	709/224
	B	US-6707796 B1	03-2004	Li	370/254
	C	US-6229787 B1	05-2001	Byrne	370/218
	D	US-6363072 B1	03-2002	Furuichi	370/395
	E	US-5854899	12-1998	Callon et al.	395/200.68
	F	US-6473421 B1	10-2002	Tappan	370/351
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.